

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and hash and shax and "sha-1" and md5	USPAT	OR	ON	2005/10/17 09:57
L2	0	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and hash and shax and md5	USPAT	OR	ON	2005/10/17 09:57
L3	0	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and hash and shax	USPAT	OR	ON	2005/10/17 09:57
L4	0	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and hash	USPAT	OR	ON	2005/10/17 09:58
L5	639	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test))))	USPAT	OR	ON	2005/10/17 09:58
L6	96	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and (test near3 vector)	USPAT	OR	ON	2005/10/17 09:59
L7	96	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and (test near3 vector) and (test message digest)	USPAT	OR	ON	2005/10/17 10:00
L8	47	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and (test near3 vector) and (test message digest) and (standard message digest)	USPAT	OR	ON	2005/10/17 10:01
L9	0	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and (test near3 vector) and (test near3 message near3 digest) and (standard near3 message near3 digest)	USPAT	OR	ON	2005/10/17 10:02
L10	0	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and (test near3 vector) and (standard near3 message near3 digest)	USPAT	OR	ON	2005/10/17 10:02
L11	0	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and (test near3 vector) and (test near3 message near3 digest)	USPAT	OR	ON	2005/10/17 10:02

L12	0	((ic (integrated near3 circuit) chip semiconductor) with ((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test)))) and (test near3 vector) and ((standard test) with message with digest)	USPAT	OR	ON	2005/10/17 10:03
L13	0	((accelerated automatic automated) near3 (testing bist (built adj in adj self adj test))) and (test near3 vector) and ((standard test) with message with digest)	USPAT	OR	ON	2005/10/17 10:04
L14	1	(test near3 vector) and ((standard test) with message with digest)	USPAT	OR	ON	2005/10/17 10:04
L15	21	("5623545").URPN.	USPAT	OR	ON	2005/10/17 10:05
L16	0	("5623545").URPN. and ((test near3 vector) ((standard test) with message with digest))	USPAT	OR	ON	2005/10/17 10:06
L17	0	("5623545").URPN. and (((standard test) with message with digest))	USPAT	OR	ON	2005/10/17 10:06
L18	0	("5623545").URPN. and ((test near3 vector))	USPAT	OR	ON	2005/10/17 10:07
L19	5	("5623545").URPN. and (shax "sha-1" md5)	USPAT	OR	ON	2005/10/17 10:09
L20	5	("5623545").URPN. and (shax "sha-1" md5 (test near3 vector))	USPAT	OR	ON	2005/10/17 10:09
L21	5	("5623545").URPN. and (shax "sha-1" md5 (test near3 vector) ((accelerated automatic automated) with testing))	USPAT	OR	ON	2005/10/17 10:18
L22	0	((accelerated near3 test near3 system) same (ic (integrated adj circuit))) and ((automated near3 test near3 equipment) same (test near6 vector near6 data)) and receiving (test near3 message near3 digest) and (standard near3 message near3 digest) and (one\$way near3 hash near3 module)	USPAT	OR	ON	2005/10/17 10:26
L24	0	(accelerated near3 test near3 system) and (ic (integrated adj circuit) semiconductor chip) and (automated near3 test near3 equipment) and (test near6 vector near6 data) and ((receiving receipt receive received reception) same (test near3 message near3 digest)) and (standard near3 message near3 digest) and (one\$way near3 hash near3 module)	USPAT	OR	ON	2005/10/17 10:29
L26	0	(accelerated near3 test near3 system) and (ic (integrated adj circuit) semiconductor chip) and ((automated automatic) near3 test near3 equipment) and (test near6 vector near6 data) and (test near3 message near3 digest) and (standard near3 message near3 digest) and (one\$way near3 hash near3 module)	USPAT	OR	ON	2005/10/17 10:32

L27	0	(accelerated near3 test near3 system) and (ic (integrated adj circuit) semiconductor chip) and ((automated automatic) near3 test near3 equipment) and (test with vector with data) and (test with message with digest) and (standard with message with digest) and (one\$way near3 hash near3 module)	USPAT	OR	ON	2005/10/17 10:32
L28	0	(ic (integrated adj circuit) semiconductor chip) and ((accelerated automated automatic) with test with (system equipment)) and (test with vector with data) and (test with message with digest) and (standard with message with digest) and (one\$way with hash with module)	USPAT	OR	ON	2005/10/17 10:34
L29	620956	((ic (integrated adj circuit) semiconductor chip) ((accelerated automated automatic) with test with (system equipment)) (test with vector with data) (test with message with digest) (standard with message with digest) (one\$way with hash with module))	USPAT	OR	ON	2005/10/17 10:35
L30	272766	((ic (integrated adj circuit) semiconductor chip) and ((accelerated automated automatic) with test with (system equipment)) (test with vector with data) (test with message with digest) (standard with message with digest) (one\$way hash module))	USPAT	OR	ON	2005/10/17 10:38
L31	796961	((ic (integrated adj circuit) semiconductor chip) ((accelerated automated automatic) with test with (system equipment)) (test with vector with data) (test with message with digest) (standard with message with digest) (one\$way hash module))	USPAT	OR	ON	2005/10/17 10:39
L32	795068	((ic (integrated adj circuit) semiconductor chip) ((accelerated automated automatic) near3 test near3 (system equipment)) (test near3 vector near3 data) (test near3 message near3 digest) (standard near3 message near3 digest) (one\$way hash module))	USPAT	OR	ON	2005/10/17 10:41
L33	618417	((ic (integrated adj circuit) semiconductor chip) ((accelerated automated automatic) near3 test near3 (system equipment)) (test near3 vector near3 data) (test near3 message near3 digest) (standard near3 message near3 digest) (one\$way near3 hash near3 module))	USPAT	OR	ON	2005/10/17 10:43
L34	2324	(ic (integrated adj circuit) semiconductor chip) and (((accelerated automated automatic) near3 test near3 (system equipment)) (test near3 vector near3 data) (test near3 message near3 digest) (standard near3 message near3 digest) (one\$way near3 hash near3 module))	USPAT	OR	ON	2005/10/17 10:43

L35	0	(ic (integrated adj circuit) semiconductor chip) and ((accelerated automated automatic) near3 test near3 (system equipment)) and (test near3 vector near3 data) and (((test near3 message near3 digest) (standard near3 message near3 digest)) and (one\$way near3 hash near3 module)	USPAT	OR	ON	2005/10/17 10:50
L36	0	(ic (integrated adj circuit) semiconductor chip) and ((accelerated automated automatic) near3 test near3 (system equipment)) and (test near3 vector near3 data) and (((standard test) near3 message near3 digest)) and (one\$way near3 hash)	USPAT	OR	ON	2005/10/17 10:51
L37	0	(ic (integrated adj circuit) semiconductor chip) and ((accelerated automated automatic) near3 test near3 (system equipment)) and (((standard test) near3 message near3 digest)) and (one\$way near3 hash)	USPAT	OR	ON	2005/10/17 10:51
L38	0	(ic (integrated adj circuit) semiconductor chip) and ((accelerated automated automatic) near3 test near3 (system equipment)) and (((standard test) near3 message near3 digest))	USPAT	OR	ON	2005/10/17 10:51
L39	1927	(ic (integrated adj circuit) semiconductor chip) and ((accelerated automated automatic) near3 test near3 (system equipment))	USPAT	OR	ON	2005/10/17 10:52
L40	238	((accelerated automated automatic) near3 (ic (integrated adj circuit) semiconductor chip) near3 (testing test) near3 (system equipment))	USPAT	OR	ON	2005/10/17 10:59
L41	36	((accelerated automated automatic) near3 (ic (integrated adj circuit) semiconductor chip) near3 (testing test) near3 (system equipment)) and ((test standard) with (vector message) with (digest data))	USPAT	OR	ON	2005/10/17 10:54
L42	1	((accelerated automated automatic) near3 (ic (integrated adj circuit) semiconductor chip) near3 (testing test) near3 (system equipment)) and ((test standard) with (vector message) with (digest data)) and (hash shax "sha-1" md5)	USPAT	OR	ON	2005/10/17 10:57
L43	1	((accelerated automated automatic) near3 (ic (integrated adj circuit) semiconductor chip) near3 (testing test) near3 (system equipment)) and ((test standard) with (vector message) with (digest data)) and (hash shax "sha-1" md5)	US-PGPUB; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/10/17 10:58
L44	1	liu.in. and ((accelerated automated automatic) near3 (ic (integrated adj circuit) semiconductor chip) near3 (testing test) near3 (system equipment))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/10/17 10:59

L45	53556	liu.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/10/17 11:01
L46	1	(accelerated test system integrated circuit automated equipment vector data message digest standard predetermined requirement one-way-hash module)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	AND	ON	2005/10/17 11:20
L47	1	(accelerated test system integrated circuit automated equipment vector data message digest standard predetermined requirement one-way-hash module).clm.	US-PGPUB	AND	ON	2005/10/17 11:19
L48	1	(IP block one-way-hash module test message digest BIST circuit main module).clm.	US-PGPUB	AND	ON	2005/10/17 11:19
L49	1	(accelerated test system integrated circuit IP block automated equipment vector data message digest standard predetermined requirement one-way-hash hardware circuit BIST).clm.	US-PGPUB	AND	ON	2005/10/17 11:19
L50	576395	(accelerated test system integrated circuit IP block automated equipment vector data message digest standard predetermined requirement one-way-hash hardware circuit BIST).clm.	US-PGPUB	OR	ON	2005/10/17 11:19
L51	277244	(IP block one-way-hash module test message digest BIST circuit main module).clm.	US-PGPUB	OR	ON	2005/10/17 11:19
L52	565834	(accelerated test system integrated circuit automated equipment vector data message digest standard predetermined requirement one-way-hash module).clm.	US-PGPUB	OR	ON	2005/10/17 11:19
L53	13720901	(accelerated test system integrated circuit automated equipment vector data message digest standard predetermined requirement one-way-hash module)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/10/17 11:21
L54	269	324/500.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L55	1079	324/537.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L56	3017	324/765.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L57	349	702/108.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L58	99	702/109.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L59	604	702/117.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25

L60	248	702/118.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L61	227	702/120.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L62	397	714/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L63	1043	714/25.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L64	1371	714/718.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L65	527	714/719.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L66	844	714/726.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L67	239	714/732.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L68	675	324/763.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L69	52	324/764.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L70	3017	324/765.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L71	176	324/766.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L72	315	324/767.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L73	109	324/768.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L74	1493	713/176.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L75	158	713/179.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L76	275	713/180.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L77	256	713/181.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L78	1159	713/193.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L79	316	713/194.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L80	1517	714/724.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L81	809	714/733.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L82	361	714/734.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L83	269	714/735.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25

L84	677	714/736.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L85	84	714/737.ccls.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:25
L86	8	(L54 L55 L56 L57 L58 L59 L60 L61 L62 L63 L64 L65 L66 L67 L68 L69 L70 L71 L72 L73 L74 L75 L76 L77 L78 L79 L80 L81 L82 L83 L84 L85) and ((automated accelerated automatic) with (test testing message) with (system equipment digest)) and (ic (integrated near3 circuit) semiconductor chip) and (shax hash md5 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/10/17 12:08
L87	68489	g06f019/00.ipc.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/10/17 12:08
L88	4	g06f019/00.ipc. and ((automated accelerated automatic) with (test testing message) with (system equipment digest)) and (ic (integrated near3 circuit) semiconductor chip) and (shax hash md5 "sha-1")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/10/17 12:09